

# AON6284

## 80V N-Channel MOSFET

## **General Description**

The AON6284 uses trench MOSFET technology that is uniquely optimized to provide the most efficient high frequency switching performance. Both conduction and switching power losses are minimized due to an extremely low combination of R<sub>DS(ON)</sub>, Ciss and Coss. This device is ideal for boost converters and synchronous rectifiers for consumer, telecom, industrial power supplies and LED backlighting.

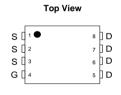
## **Product Summary**

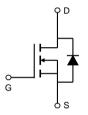
 $\begin{array}{lll} V_{DS} & 80V \\ I_{D} \; (at \; V_{GS} \! = \! 10V) & 78A \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 10V) & < 7.1 m\Omega \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 6V) & < 10 m\Omega \end{array}$ 

100% UIS Tested 100%  $R_g$  Tested









Absolute Maximum Ratings T <sub>A</sub> =25°C unless otherwise noted						
Parameter		Symbol	Maximum	Units		
Drain-Source Voltage		V <sub>DS</sub>	80	V		
Gate-Source Voltage		V <sub>GS</sub>	±20	V		
Continuous Drain Current	T <sub>C</sub> =25°C	ı	78			
	T <sub>C</sub> =100°C	I <sub>D</sub>	49	A		
Pulsed Drain Current C		I <sub>DM</sub>	170			
Continuous Drain Current	T <sub>A</sub> =25°C	1	24	Δ.		
	T <sub>A</sub> =70°C	IDSM	19	Α Α		
Avalanche Current <sup>C</sup>		I <sub>AS</sub>	40	A		
Avalanche energy L=0.1mH <sup>C</sup>		E <sub>AS</sub>	80	mJ		
	T <sub>C</sub> =25°C	В	78	W		
Power Dissipation <sup>B</sup>	T <sub>C</sub> =100°C	P <sub>D</sub>	31	VV		
	T <sub>A</sub> =25°C	В	7.4	10/		
Power Dissipation <sup>A</sup>	T <sub>A</sub> =70°C	P <sub>DSM</sub>	4.7	W		
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C		

Thermal Characteristics							
Parameter	Symbol Typ		Max	Units			
Maximum Junction-to-Ambient A	t ≤ 10s	D	14	17	°C/W		
Maximum Junction-to-Ambient AD	Steady-State $R_{\theta JA}$		40	55	°C/W		
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	1.3	1.6	°C/W		



#### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V		80			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS}$ =80V, $V_{GS}$ =0V	_			1	
	Zero Gate Voltage Drain Current		T <sub>J</sub> =55°C			5	μА
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS,}I_{D}=250\mu A$		2.3	2.8	3.3	V
$I_{D(ON)}$	On state drain current	V <sub>GS</sub> =10V, V <sub>DS</sub> =5V		170			Α
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =20A			5.9	7.1	mΩ
			T <sub>J</sub> =125°C		9.5	11.4	11122
		V <sub>GS</sub> =6V, I <sub>D</sub> =20A			7.6	10	mΩ
<b>g</b> FS	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =20A			66		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V			0.71	1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current					78	Α
DYNAMIC	PARAMETERS						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =40V, f=1MHz			2162		pF
C <sub>oss</sub>	Output Capacitance				300		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				16		pF
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		0.6	1.35	2.1	Ω
SWITCHI	NG PARAMETERS					•	•
<b>Q</b> <sub>g</sub> (10V)	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =40V, I <sub>D</sub> =20A			28	40	nC
$Q_{gs}$	Gate Source Charge				8.5		nC
$Q_{gd}$	Gate Drain Charge				4.5		nC
t <sub>D(on)</sub>	Turn-On DelayTime				9		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =40V, $R_L$ =2 $\Omega$ , $R_{GEN}$ =3 $\Omega$			4.5		ns
$t_{D(off)}$	Turn-Off DelayTime				23		ns
t <sub>f</sub>	Turn-Off Fall Time				5		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, dI/dt=500A/μs			26		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	I <sub>F</sub> =20A, dI/dt=500A/μs			118		nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25° C. The Power dissipation  $P_{DSM}$  is based on  $R_{\theta JA}$  t  $\leq$  10s and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design.

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B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$ =150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub>=150° C. Ratings are based on low frequency and duty cycles to keep initial T<sub>.1</sub>=25° C.

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using  $<300\,\mu s$  pulses, duty cycle 0.5% max.

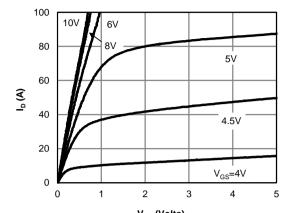
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(MAX)}$ =150° C. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

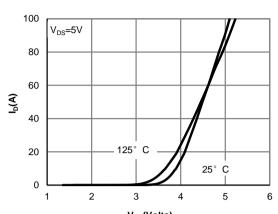
H. These tests are performed with the device mounted on 1 in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ$  C.



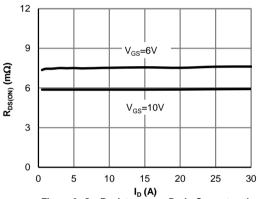
#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



V<sub>DS</sub> (Volts) Fig 1: On-Region Characteristics (Note E)



V<sub>GS</sub>(Volts)
Figure 2: Transfer Characteristics (Note E)



I<sub>D</sub> (A)
Figure 3: On-Resistance vs. Drain Current and
Gate Voltage (Note E)

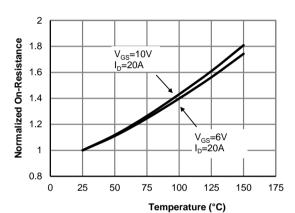
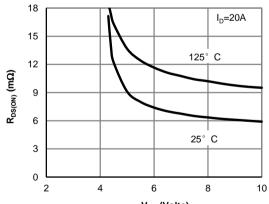
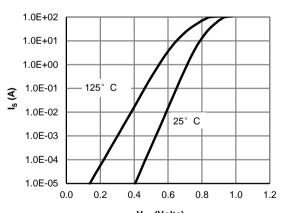


Figure 4: On-Resistance vs. Junction Temperature (Note E)



V<sub>GS</sub> (Volts) Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)



V<sub>SD</sub> (Volts) Figure 6: Body-Diode Characteristics (Note E)



#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

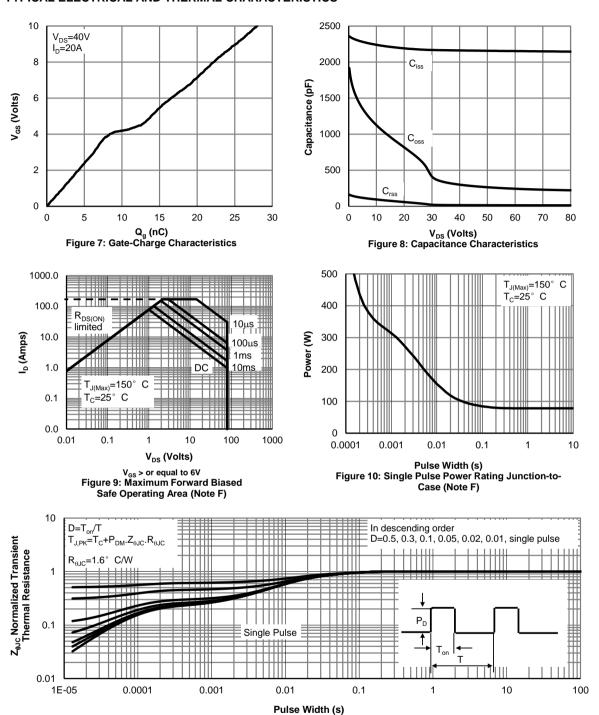
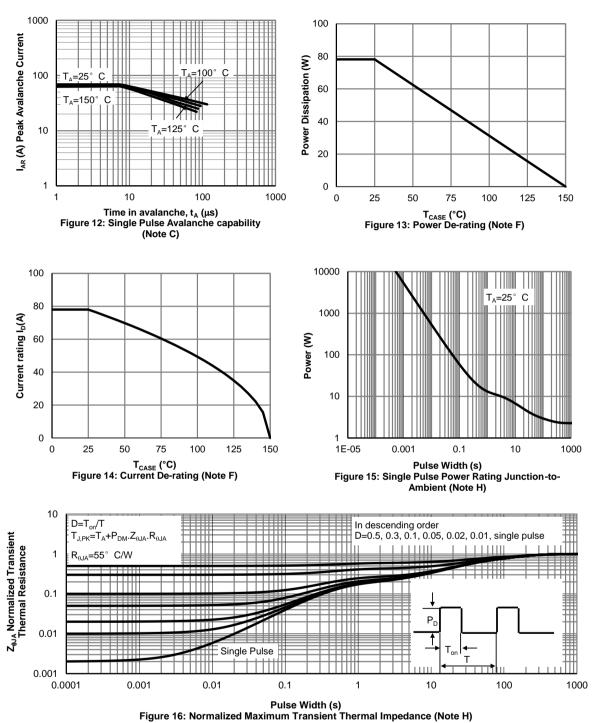


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

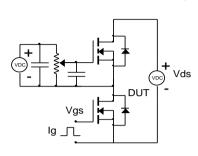


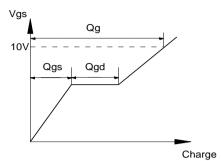
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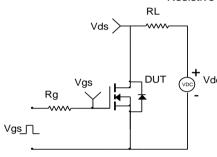


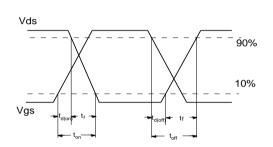
### Gate Charge Test Circuit & Waveform



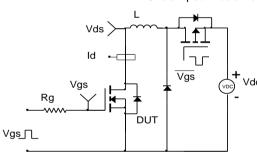


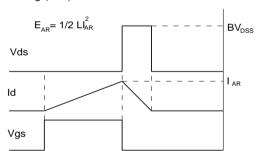
## Resistive Switching Test Circuit & Waveforms





### Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





### Diode Recovery Test Circuit & Waveforms

